Search Notes



Applicant(s)/Patent under Reexamination

3751

10/562,871 GRUBER ET AL.
Examiner Art Unit

Huyen Le

SEARCHED					
Class	Subclass	Date	Examiner		
401	270 271 272 275 280 292	9/10/2009	HL		
	263 132				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examine	
US-F	BPUB	9/14/2009	HL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
,	DATE	EXMR	